



PRODUCT/PROCESS CHANGE NOTIFICATION
Generic Copy

12-OCT-2001

SUBJECT: Final Product/Process Change Notification #11329

**TITLE: Final Notification for Transferring the SOT-223 Package From ON Semiconductor
Phillipines To Psi**

EFFECTIVE DATE: 11-Dec-2001

AFFECTED CHANGE CATEGORIES: On Semiconductor Assembly & Test Sites

AFFECTED PRODUCT DIVISION: Analog Products

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Joe Duffalo <FFBH9W@onsemi.com>

SAMPLES: No

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact Sales Office or Mouayed Saleh <R12646@onsemi.com>

DISCLAIMER:

Final Product/Process Change Notification (FPCN) - Final Notification completing the notification process. Distributed at least 60 days from the effective date of the change. ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE :

This is the Final Notification to the Initial Notification #11329 that was issued on April 12, 2001. ON Semiconductor has selected Pacific Semiconductor Incorporated (PSI) to be an assembly and test site for the SOT-223 package. PSI is a qualified site for other analog packages for many years. All SOT-223 devices that are currently being built at ON Semiconductor site (Carmona, Philippines) will be moved to PSI. All SOT-223 lead frames will be converted from Nickel/Palladium (Ni/Pd) to Tin/Lead (Sn/Pb). The lead frame and assembly site changes will not effect the case outline, electrical, or thermal characteristics of the devices.

QUALIFICATION DATA :

TEST NAME & #	TEST CONDITIONS	Accept	Read Point	SS	Lots
High Temp HTOL 02 Operating Life	Ta = 125DegC for 1008 hrs or Ta = 150DegC for 504 hrs	c=0	0,504,1008	80	3
High Temp HTS 03 Storage	Ta = 175DegC for 504 hrs	c=0	0,504,1008	80	1
Highly HAST- 05 Accelerated PC Stress Test	Ta =131DegC,RH = 85% biased	c=0	0,48,96,144	80	3



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TEST NAME & #	TEST CONDITIONS	Accept	Read Point	SS	Lots
Autoclave AC-PC 06	Ta =121DegC, RH=100%	c=0	0,48,96,144	80	3
Temp TC-PC 07	Ta = -65DegC to	c=0	0,500,1000	80	3
Cycling	+150DegC for 500 cycles				

RELIABILITY DATA SUMMARY:

Table III. Results of Non-Preconditioned Reliability Tests

	HTOL		HTS	
	Read Point (Cycles)		Read Point (Cycles)	
LOT ID	250	504	504	1008
PPF-1	0/77	0/77	0/77	0/77
PPF-2	0/77	0/77	0/77	0/77
PPF-3	0/77	0/77	0/77	0/77
CU-1	0/77	0/77	0/77	0/77
CU-2	0/77	0/77	0/77	0/77
CU-3	0/77	0/77	0/77	0/77
Control	0/77	0/77	0/77	0/77

Table IV. Results of Preconditioned Reliability Tests

	HAST			AC			TC	
	Read Point (Hrs)			Read Point (Hrs)			Read Point (Cycles)	
LOT ID	48	96	144	48	96	144	500	1000
PPF-1	0/77	0/77	0/77	0/77	0/77	0/77	0/77	0/77
PPF-2	0/77	0/77	0/77	0/77	0/77	0/77	0/77	0/77
PPF-3	0/77	0/77	0/77	0/77	0/77	0/77	0/77	0/77
CU-1	0/77	0/77	0/77	0/77	0/77	0/77	0/77	0/77
CU-2	0/77	0/77	0/77	0/77	0/77	0/77	0/77	0/77
CU-3	0/77	0/77	0/77	0/77	0/77	0/77	0/77	0/77
Control	0/77	0/77	0/77	0/77	0/77	0/77	0/77	0/77

ELECTRICAL CHARACTERISTIC SUMMARY: N/A

CHANGED PART IDENTIFICATION:

None, wafer genealogy can be determined from data code information marked on the device.

RELATED NOTIFICATIONS:

#11329 - INITIAL NOTIFICATION FOR TRANSFERRING THE SOT-223 PACKAGE FROM ON SEMICONDUCTOR PHILLIPINES TO PSI

AFFECTED DEVICE LIST (WITHOUT SPECIALS)

PART

LM317MBSTT1
 LM317MBSTT3
 LM317MSTT1
 LM317MSTT3
 MC33269ST-3.3R2
 MC33269ST-3.3T3
 MC33275ST-2.5R2
 MC33275ST-2.5T3
 MC33275ST-3.0R2
 MC33275ST-3.0T3
 MC33275ST-3.3R2
 MC33275ST-3.3T3

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MC33275ST-5.0R2
MC33275ST-5.0T3
MC33375ST-1.8R2
MC33375ST-1.8T3
MC33375ST-2.5R2
MC33375ST-2.5T3
MC33375ST-3.0R2
MC33375ST-3.0T3
MC33375ST-3.3R2
MC33375ST-3.3T3
MC33375ST-5.0R2
MC33375ST-5.0T3
MC34268STT1
MC34268STT3
NCP1117ST12T3
NCP1117ST15T3
NCP1117ST18T3
NCP1117ST20T3
NCP1117ST25T3
NCP1117ST285T3
NCP1117ST33T3
NCP1117ST50T3
NCP1117STAT3
XC33269STR2
XC33269STT3